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Workshop on Ion Beam Studies of Nanomaterials: Synthesis, Modification and Characterization | (smr 1758)

Monday 26 June 2006

Fully atomistic approach for ion channeling analysis of defects in Si - Adriatico Guest
House Giambiagi Lecture Hall (11:30-12:30)

time	title	presenter
11:30	Fully atomistic approach for ion channeling analysis of defects in Si	G. LULLI (CNR, BOLOGNA)